Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/712,354	LARSEN, MIKAEL BLIKSTED
Examiner	Art Unit
TAN Q. NGUYEN	3661

SEARCHED				
Class	Subclass	Date	Examiner	
701	21,207	11/4/2005	TN	
	213,214			
367	130,131			
	124			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
PLUS SEARCH	4/5/2004	TN
EAST SEARCH	11/7/2005	TN
IEEE SEARCH (SEE ATTACHED)	11/7/2005	TN
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